

Epitaxial growth of ultrathin palladium films on Re{0001}

Article

Accepted Version

Etman, H. A., Zheleva, Z. V., Held, G. and Bennett, R. A. ORCID: https://orcid.org/0000-0001-6266-3510 (2011) Epitaxial growth of ultrathin palladium films on Re{0001}. The Journal of Physical Chemistry C, 115 (10). pp. 4191-4199. ISSN 1932-7447 doi: https://doi.org/10.1021/jp112136f Available at https://centaur.reading.ac.uk/19500/

It is advisable to refer to the publisher's version if you intend to cite from the work. See Guidance on citing.

To link to this article DOI: http://dx.doi.org/10.1021/jp112136f

Publisher: American Chemical Society

All outputs in CentAUR are protected by Intellectual Property Rights law, including copyright law. Copyright and IPR is retained by the creators or other copyright holders. Terms and conditions for use of this material are defined in the End User Agreement.

www.reading.ac.uk/centaur

CentAUR

Central Archive at the University of Reading



Reading's research outputs online

Supporting Information

The epitaxial growth of ultra-thin palladium films on $Re\{0001\}$

Haitham A. Etman, Zhasmina V. Zheleva, Georg Held and Roger A. Bennett^a

School of Chemistry, University of Reading, Reading, RG6 6AD, UK

LEED-IV Calculations

Bulk diffraction was calculated using Pendry's layer doubling method for Re bulk inter-layer spacings of 2.23Å. Scattering phase shifts for Re and Pd atoms were calculated as a function of energy using the program package provided by Barbieri and Van Hove¹. The maximum angular momentum quantum number was set to 9. The imaginary and real parts of the inner potential were set to 4.4eV and -11.4eV (4.1 and -12.8eV), respectively for the clean surface (Pd film). Initially, the radial root mean square displacement for Re and Pd were assumed to be 0.084Å and 0.09Å, respectively. In the final stage of the searches the displacements were optimized together with the inner potential to obtain the best fit between theory and experiment. The

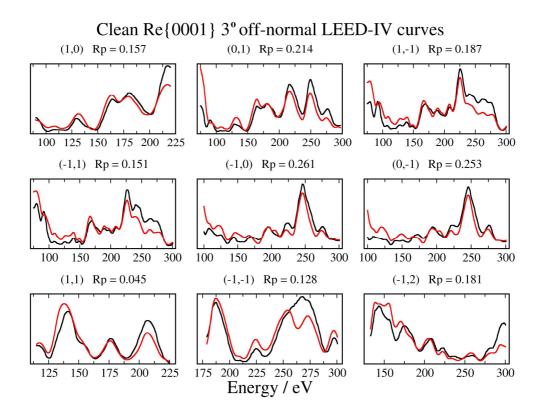
^a E-mail: <u>r.a.bennett@reading.ac.uk</u>, Telephone: +44 (0)118 378 8559

downhill simplex method was used for the structure optimization ². RR is the reliability of the R-

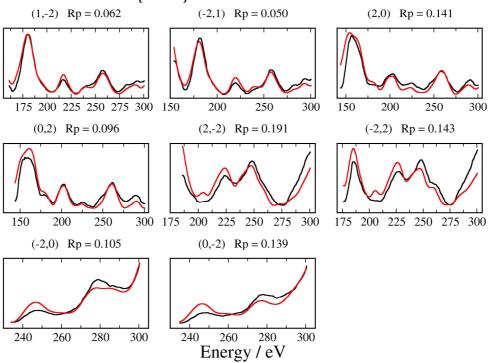
factor (R_P), $RR = \sqrt{\frac{8V_i}{\Delta E}}$, where V_i is the optical potential and ΔE is the total energy range analysed.

LEED-IV Figures

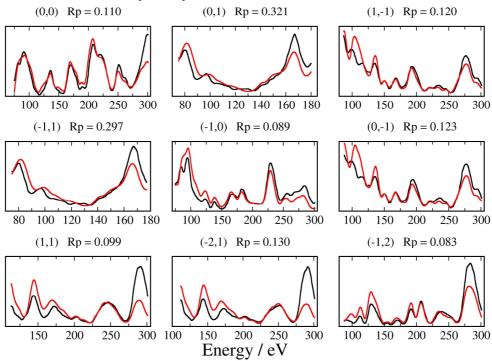
The full set of LEED-IV data and best fit curves are given in the following sets of images. For each the title is self explanatory and the black curves the data and the red curves the best fits. Individual R_P values are indicated for each fit.



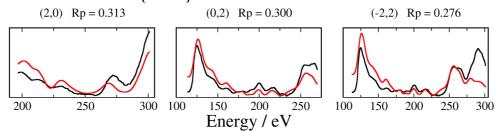
Clean Re{0001} 3° off-normal LEED-IV curves



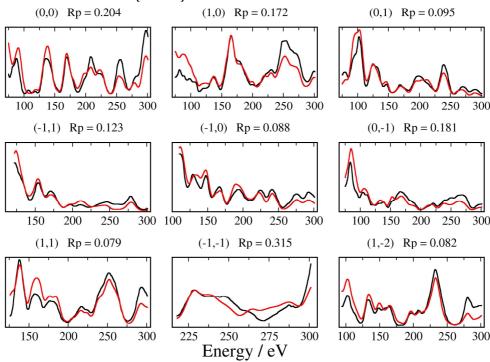
Clean Re{0001} -7° off-normal LEED-IV curves



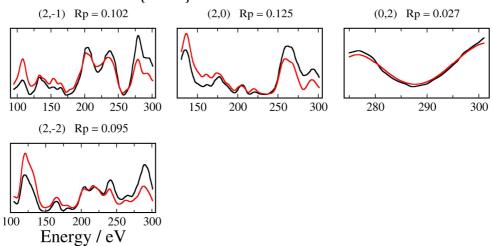
Clean Re{0001} -7° off-normal LEED-IV curves

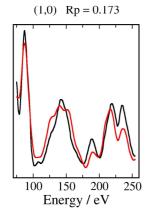


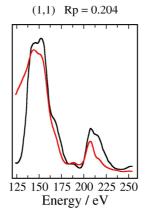
Clean Re{0001} 10° off-normal LEED-IV curves

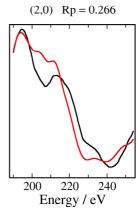


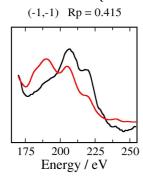
Clean Re{0001} 10° off-normal LEED-IV curves

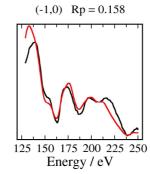


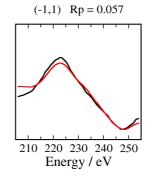


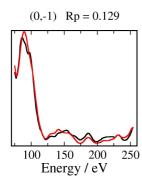


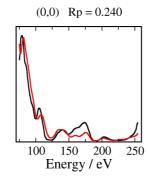


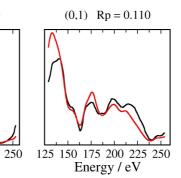


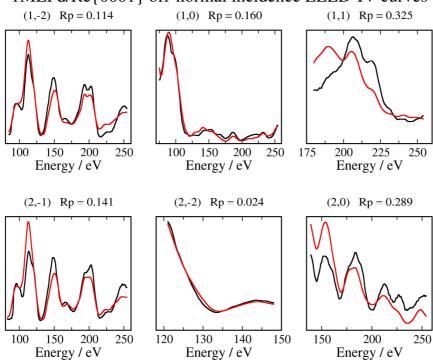


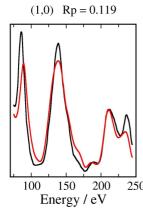


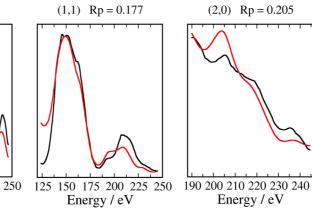


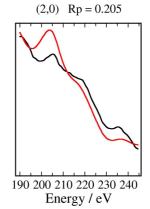


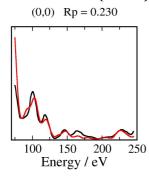


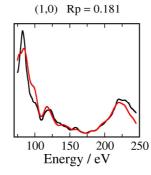


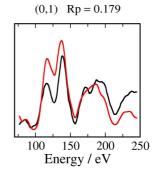


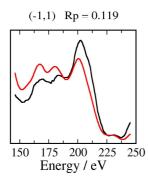


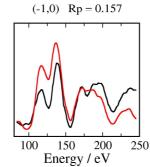


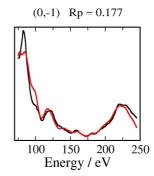


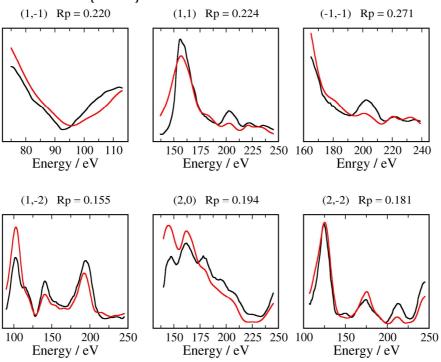


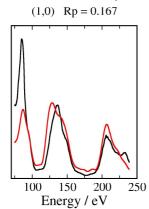


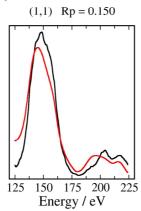


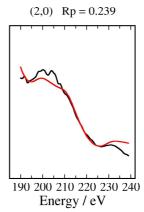


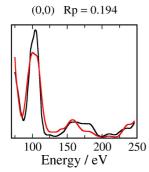


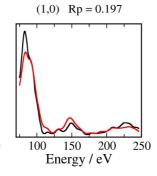


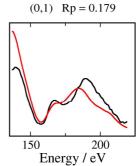


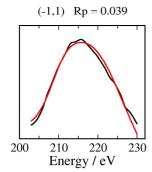


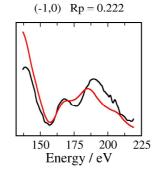


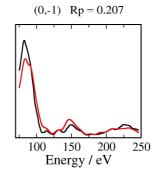


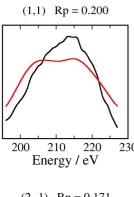


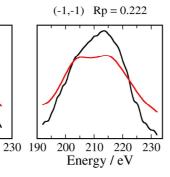


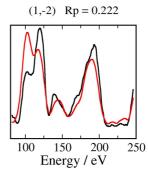


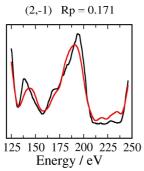


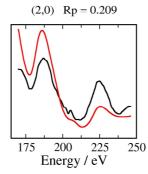


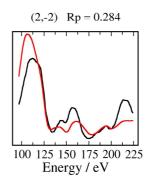


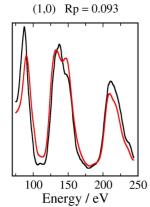


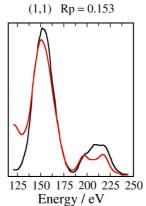


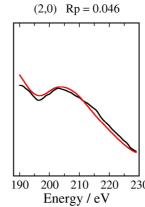


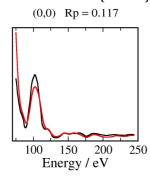


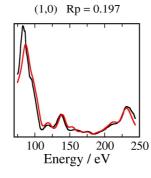


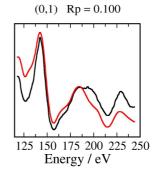


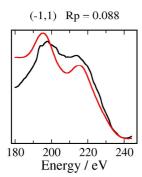


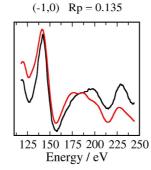


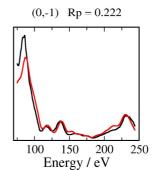


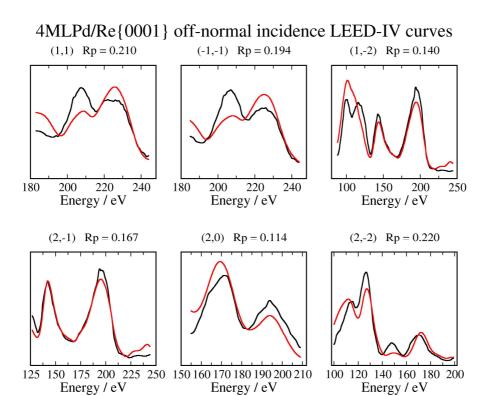












Supplementary References

1 Barbieri, A.; Van Hove, M. A. *Phase shift program package*, available from http://electron.lbl.gov/software/software.html

2 Press, W. H.; Flannery, B. P.; Teukolsky, S. A.; Vetterling, W. T. *Numerical Recipes in C*: Cambridge University Press: Cambridge, 1988.